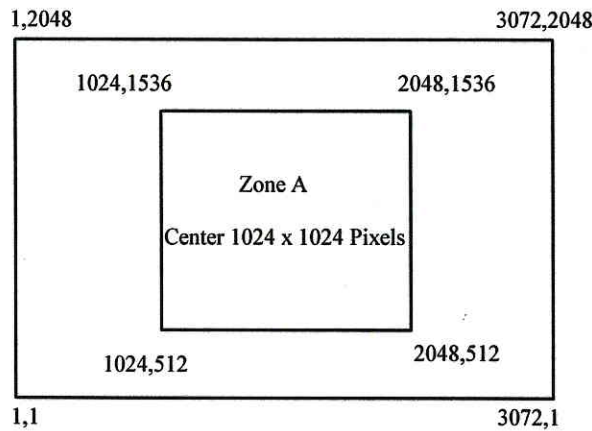


4.3 Cosmetic Classification

Defect tests performed at T=25°C

Class	Point Defects		Cluster Defects		Maximum Cluster Size	Column Defects	
	Total	Zone A	Total	Zone A		Total	Zone A
C1	≤35	≤14	≤5	≤2	2	0	0
C2	≤90	≤45	≤36	≤18	5	0	0



- Point Defect
 - Dark: A pixel which deviates by more than 6% from neighboring pixels when illuminated to 70% of saturation, OR
 - Bright: A Pixel with dark current > 10,000 e/pixel/sec at 25°C.
- Cluster Defect
 - A grouping of not more than "Maximum Cluster Size" defects
- Column Defect
 - A grouping of >5 contiguous point defects along a single column, OR
 - A column containing a pixel with dark current > 30,000e/pixel/sec, OR A column that does not meet the CTE specification for all exposures less than the specified Max sat. signal level and greater than 2 Ke, OR
 - A pixel which loses more than 250 e under 2Ke illumination.
- Neighboring pixels
 - The surrounding 128 x 128 pixels or ±64 columns/rows.
- Defect Separation
 - Column and cluster defects are separated by no less than two (2) pixels in any direction (excluding single pixel defects).
- Defect Region Exclusion
 - Defect region excludes the outer two (2) rows and columns at each side/end of the sensor.



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